## Notice of References Cited Application/Control No. 10/634,536 Examiner Kamran Afshar, 571-272-7796 Applicant(s)/Patent Under Reexamination NAIR ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2002/0059434 A1	05-2002	Karaoguz et al.	709/228
	В	US-2003/0227892 A1	12-2003	Cabana, Joseph	370/338
	С	US-2005/0064866 A1	03-2005	Sun et al.	455/426.1
	D	US-6,625,451	09-2003	La Medica et al.	455/434
	Е	US-2004/0205158 A1	10-2004	Hsu, Raymond T.	709/227
	F	US-2003/0134636 A1	07-2003	Sundar et al.	455/432
	G	US-5,903,832	05-1999	Seppanen et al.	455/435.3
	Н	US-			
	I	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р			· · · · ·		
	Ø					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	v							
	w							
	x							

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.